Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 02103-603001	Application No. 10/789,695	
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CER \$1 98(b))		Applicant Barret Lippey, et al.		
		Filing Date	Group Art Unit	
		February 27, 2004	2862	

	· · · · · · · · · · · · · · · · · · ·		U.S. Pate	nt Documents				
Examiner Initial	Desig. ID	Document Number	Issue / Pub Date	Patentee	Cla	ass	Subclass	Filing Date If Appropriate
	AA	3,942,869	03-1976	Portner et al.	999999		000000	
	AB	5,497,207	03-1996	Kim	200000000		30000000	
	AC	5,526,063	06-1996	Joubert et al.	99999000		0000000	
	AD	5,765,934	06-1998	Okamori et al.	0000000		888888	
	AE	6,183,091	02-2001	Johnson et al.	0000000			
	AF	6,398,389	06-2002	Bohler	000000000		00000000	
	AG	6,648,475	11-2003	Roddy et al.		ļ	9,000	
	AH	6,688,747	02-2004	Wichner et al.			00000	
	AI	6,733,139	05-2004	Childers	***************************************		80000000	
	AJ	6,769,774	08-2004	McDowell			0000	
	AK	6,847,483	01-2005	Lippey et al.	2000		900000	
	AL	6,956,702	10-2005	Pate	***************************************		2000	
	AM	6,969,177	11-2006	Li et al.	20000000		00000000	
	AN	6,988,806	01-2006	Slobodin et al.	2000000		0000000	
	AO	7,035,006	04-2006	Umeya et al.	0000000			
	AP	7,040,764	05-2006	Przybyla et al.	200000		250000000	
	AQ	7,234,817	06-2007	Paukshto	0000000		50000000	
	AR	US2002/0145708	10-2002	Childers et al.			000000	
	AS	US2002/186349	12-2002	Wichner	0000000			
	AT	US2003/0179346	09-2003	Mihara				
	AU	US2003/0002016	01-2003	Sellen et al.				
-	AV	US2004/0044445	04-2002	Bohler	555500		9000	

	Foreign Patent Documents or Published Foreign Patent Applications							
Examiner	Desig.	Document	Publication	Country or			Trans	slation
Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
	AW	0 493 863	07-1992	EPO	10000511500000	200525888888888888888888888888888888888		
	AX	0 490 391	06-1992	EPO	1000500005000	\$5000500055000550005000		

Examiner Signature	/Christopher Mahoney/	Date Considered 05/27/2008
EXAMINER: Initials cita	9	ot in conformance and not considered. Include copy of this form with

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1	losure Statement plicant	Applicant Barret Lippey, et al.		
(Use several shot) (37 CFR §1.98(b))	eets if necessary)	Filing Date February 27, 2004	Group Art Unit 2862	

	Foreig	n Patent Docur	nents or Pub	lished Foreign I	Patent A	Applicatio	ns	
Examiner	Desig.	Document	Publication	Country or			Trans	lation
Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
	AY	1341387	09-2003	EPO	900000	5000000		
	AZ	2001-005412	01-2001	Japan	000000000000000000000000000000000000000	000000000000000000000000000000000000000	X Abstr.	
	AAA	2001-305649	11-2001	Japan	200000000000000000000000000000000000000	2000000	X Abstr.	
	ABB	2001-264750	09-2001	Japan	900000	000000000000000000000000000000000000000	X Abstr.	
	ACC	H07-152088	06-1995	Japan	80000	000000000000000000000000000000000000000	X Abstr.	······································
	ADD	H10-312027	11-1998	Japan	000000000000000000000000000000000000000		X Abstr.	
	AEE	H11-174232	07-1999	Japan	10000000000000000000000000000000000000	00000	X Abstr.	
	AFF	H04-219745	08-1992	Japan	000000000000000000000000000000000000000		X Abstr.	
	AGG	H07-503348	07-1994	Japan	0000000000	2000000	X Abstr.	
	АНН	2388992	11-2003	Great Britain	2000000	000000000		
	AII	2004-004821	01-2004	Japan	2000000		X Abstr.	
	AJJ	2004-029267	01-2004	Japan	800		X Abstr.	
	AKK	6-082747	03-1994	Japan	990000000	900	X Abstr.	
	ALL	7261274	10-1995	Japan	240000000000000000000000000000000000000	120000000000000000000000000000000000000	X Abstr.	
	AMM	WO1997/01610	01-1997	WIPO	0000	00000000		
	ANN	WO1993/15585	08-1993	WIPO	7000000	2000		
	AOO	WO03/034145	04-2003	WIPO	1	8		····

	Other Documents (include Author, Title, Date, and Place of Publication)				
Examiner	Desig.				
Initial	ID	Document			
	APP	High Reflectors. Datasheet [online]. JK Consulting, 2003 [retrieved on 2007-09-10]. Retrieved from the Internet: <url:http: hr's.htm="" kruschwitz.com="">.</url:http:>			
	AQQ	Young, L., "Multilayer Interference Filters with Narrow Stop Bands:, Applied Optics, vol. 6(2), pp. 297-312 (02-1967).			
	ARR	Pelletier et al., "Interference Filters with Multiple Peaks", J. Opt. Soc. Am., vol. 72(6), pp. 683-687 (06-1982).			

Examiner Signature /Christopher Mahoney/	Date Considered 05/27/2008				
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Information Disclosure Statement by Applicant		Applicant Barret Lippey, et al.		
(Use several sh	eets if necessary)	Filing Date February 27, 2004	Group Art Unit 2862	

(Other D	ocuments (include Author, Title, Date, and Place of Publication)
Examiner Initial	Desig. ID	Document
mitiai	ASS	EP Examination Report in Application No. 02102872.5, dated October 18, 2004.
	ATT	EP Examination Report in Application No. 02102872.5, dated May 13, 2005.
	AUU	EP Examination Report in Application No. 05101098.1, dated October 6, 2005.
	AVV	EP Examination Report in Application No. 02102872.5, dated March 17, 2006.
	AWW	International Search Report in Application No. PCT/US2006/000493, dated June 16, 2006.
	AXX	EP Examination Report in Application No. 05101098.1, dated February 16, 2007.
	AYY	EP Search Report in Application No. 05101103.9, dated March 2, 2007.
	AZZ	EP Partial Search Report in Application 07102106.7, dated May 18, 2007.
	AAAA	EP Search Report in Application 07102106.7, dated November 7, 2007.
	ABBB	CN Office Action in Application No. 02157897.4, dated June 8, 2007.
	ACCC	International Preliminary Report on Patentability in corresponding Application No. PCT/US2006/000493, dated July 19, 2007.
	ADDD	IN Examination Report in Application No. 1064/MUM/2002, dated 4/10/2008.
	AEEE	JP Examination Report in Application No. 2002-371849, dated March 27, 2008.
	AFFF	Office Action in related Application No. 10/931,608, dated August 25, 2005.
	AGGG	Office Action in related Application No. 10/931,608, dated April 17, 2006.
	АННН	Office Action in related Application No. 11/033,214, dated December 15, 2006.
	AIII	Office Action in related Application No. 10/893,461, dated January 5, 2007.
	AJJJ	Office Action in related Application No. 11/548,373, dated April 26, 2007.
	AKKK	Office Action in related Application No. 10/893,461, dated May 7, 2007.
	ALLL	Office Action in related Application No. 11/033,214, dated September 13, 2007.
	AMMM	Office Action in related Application No. 11/127,531, dated September 27, 2007
	ANNN	Office Action in related Application No. 10/893,461, dated February 15, 2008.
	AOOO	Office Action in related Application No. 11/548,373, dated April 1, 2008.
	APPP	

Examiner Signature /Christopher Mahoney/	Date Considered 05/27/2008				
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